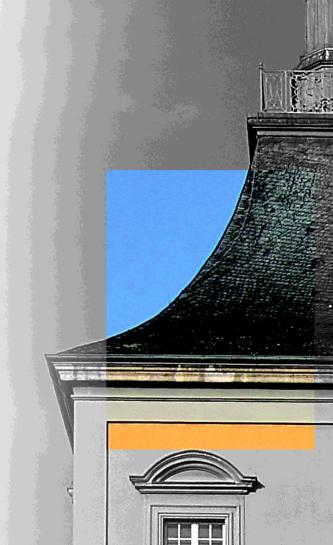


# TERASCALE WORKSHOP 2019 SERIAL POWERING IN PIXEL DETECTORS

Matthias Hamer, University of Bonn





- why serial powering?

- key ingredients for a serially powered silicon pixel detector

- challenges in serial powering



- why serial powering?
- of the ATLAS Pixel Detector as an mole - most of what will be shown applies to the CNIS upgrade in a very - key ingredients for a serially powered silicon pixel detector
- challenges in serial powering

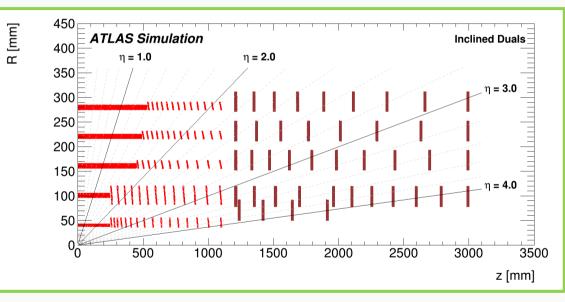
Il mostly use the planned upgrade



## ATLAS INNER TRACKER PIXEL DETECTOR

#### - 5 barrel layers:

- flat section up to z = 500mm
- inclined section up to z = 1200mm
- endcap rings up to z = 3000mmm
- coverage of tracks with  $|\eta| < 4$
- about 10.000 hybrid pixel modules
  - ightarrow about 40.000 FE chips
- 50x50  $\mu m^2$  or 25x100  $\mu m^2$  pixels
- 2 innermost layers will be replaceable after collecting 2000 fb<sup>-1</sup>



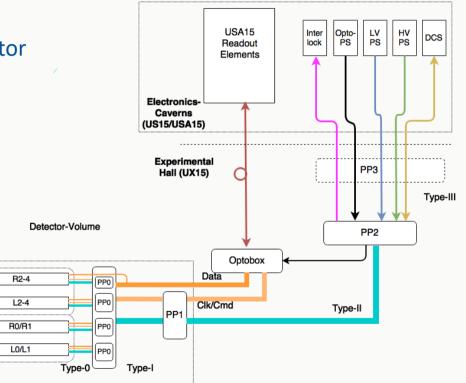
#### Candidate Layout for the ATLAS Pixel Upgrade

- general reference: CERN-LHCC-2017-21; ATLAS-TDR-030



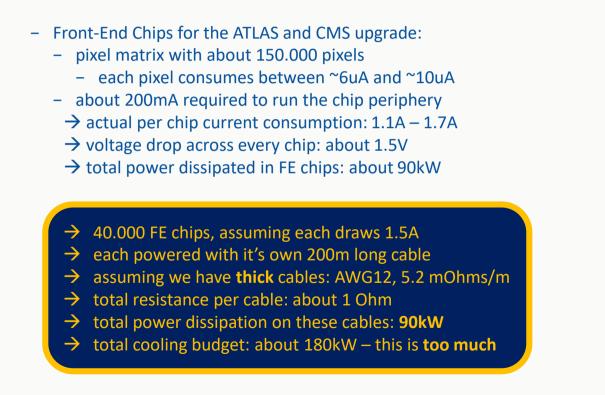
## SERVICES OVERVIEW

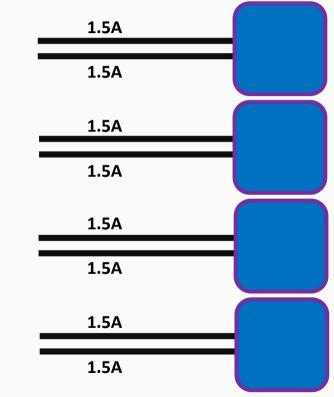
- services overview of the ATLAS ITk Pixel Detector
  - off-detector services
    - power supplies, readout electronics
    - Type-3 cables, about 60m-80m long
    - Type-2 cables, about 12m long
  - on-detector services
    - Type-1 cables, about 6m long
    - Type-0 services, about 1m long
  - → typical current path for a power line: about 200m





### PARALLEL POWERING?







### SERIAL POWERING

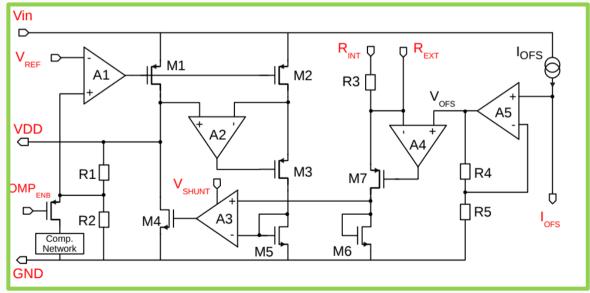
- recycle the current on-detector
  - average serial powering modularity: 8 modules
  - assuming single chip modules: losses on cables go down to 11kW
  - the number of cable we require also goes down by a factor of 8
    - $\rightarrow$  less material in the detector
  - the number of required power supplies goes down by a factor of 8
    - ightarrow less space required in services caverns
- advantages come at a cost
  - actual current consumption per FE depends on instantaneous hit-rate
    - $\rightarrow$  different instantaneous current consumption for all FE chips in a chain
  - voltage drop from one module to the next
    - ightarrow need AC coupled data transmission
    - $\rightarrow$  with 3D modules: length of serial powering chain limited!
    - ightarrow biasing of sensors can get a little tricky
    - $\rightarrow \dots$

1.5A	
1.5A	



# HOW TO POWER A SERIAL POWERING CHAIN

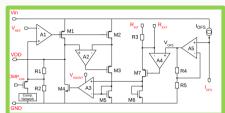
- provide as much current to the full chain at all times as we expect at peak hit-rate
   → constant current source
- each chip requires a local voltage regulator and a shunt to draw any surplus current
   → Shunt-LDO regulator

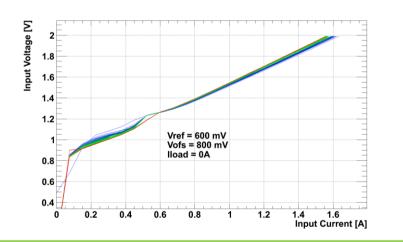




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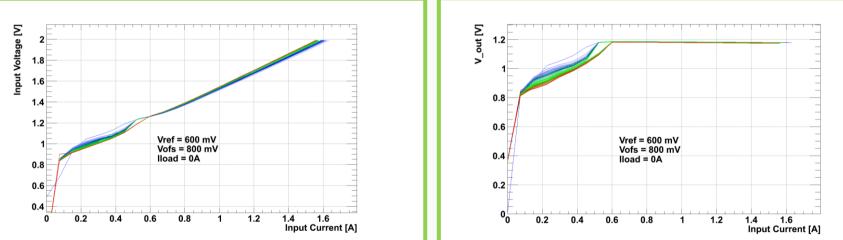
from the outside, this looks like a voltage source (Voffset) connected in series to a resistor (R3/k)

 $\rightarrow$  constant voltage drop at constant current independent of actual chip current consumption



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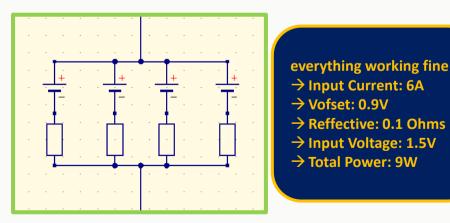
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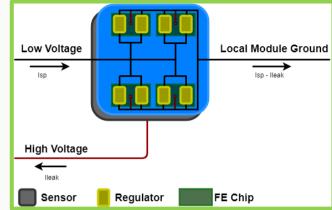
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WHAT IF?

- a chip in the chain becomes high-ohmic?
  - the rest of the chain would be disabled
  - mitigate problem by connecting chips in parallel
    - $\rightarrow$  SLDO regulators need to be able to shunt the extra current
    - ightarrow total voltage drop over the module must not exceed limits for safe operation
    - ightarrow thermal management of the module must be able to handle the extra power

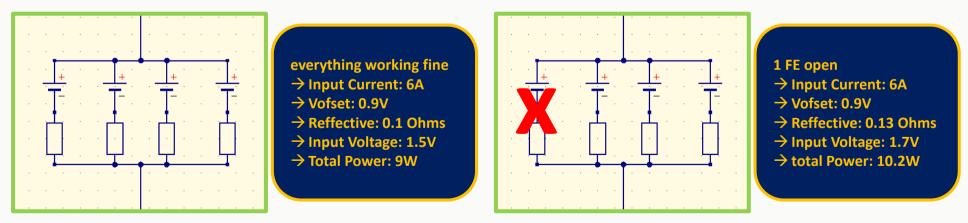


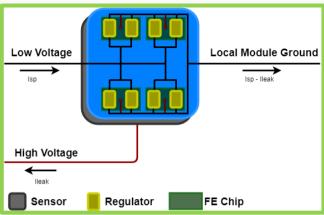




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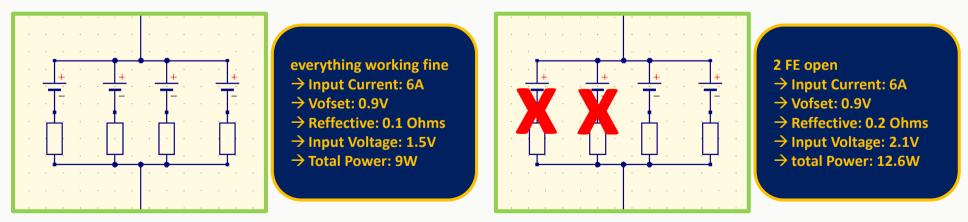


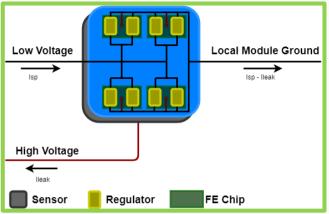




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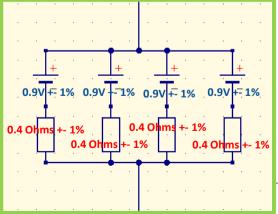






## OPERATING CHIP IN PARALLEL AGAIN...

- the FE chips on a module are operated in parallel:
  - ightarrow single sensor tile, DC coupled: same ground potential required
  - $\rightarrow$  current distribution becomes a challenge
    - ightarrow voltage drop on all regulators is the same
    - $\rightarrow$  offset voltage and slope determined by external resistors: small differences O(1%) expected
    - ightarrow not every FE gets exactly 25% of the total current
    - ightarrow hit-rate can spike significantly: increase load current in single regulators
      - ightarrow compensate by supplying more current than nominally required: shunt current overhead
        - $\rightarrow$  how much?



higher offset: lower current through resistor higher resistor: lower current through resistor

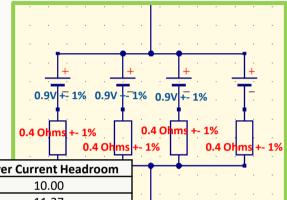
#### worst case:

→ downwards fluctuation for both offset and slope in all other chips (Chips 1, 2, 3)
 → upwards fluctuation for both offset and slope in one chip (Chip 4)
 → Chip 4 gets significantly smaller current





- worst case scenario for a quad chip module:
  - 10% shunt current headroom supplied
  - 1% variation in offset and slope: 5% difference in terms of current
  - half of the safety we have



	Slope [Ohms]	Offset resistor [kOhms]	Offset [V]	Serial Current [A]	Voltage Drop [V]	<b>Required Current</b>	Leftover Current Headroom	
Module	0.10		0.90	6.00	1.49	5.45	10.00	
FE 1	0.39	445.50	0.88	1.52	1.49	1.36	11.37	
FE 2	0.39	445.50	0.88	1.52	1.49	1.36	11.37	
FE 3	0.39	445.50	0.88	1.52	1.49	1.36	11.37	
FE 4	0.41	454.50	0.92	1.44	1.49	1.36	5.90	
Target	0.40	450.00		0.05				

required current depends on hit-rate

- hit-rate can only be roughly estimated from simulation
- variations of up to 10% seen between simulation and measurement in current detector

1% variation in offset and slope in combination with a 10% variation in hit-rate leaves almost no headroom

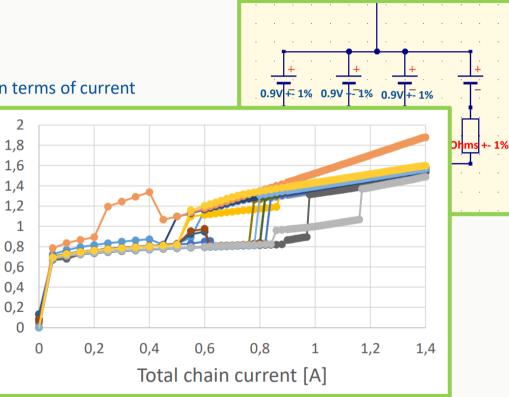


### AN EXAMPLE

- worst case scenario for a quad chip module:
  - 10% shunt current headroom supplied
  - 1% variation in offset and slope: 5% difference in terms of current
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	Slope [Ohms]	Offset resistor [kOhms]	Offset [V]	Serial Currer
Module	0.10		0.90	6.00
FE 1	0.40	445.50	0.89	1.52
FE 2	0.40	445.50	0.89	1.52
FE 3	0.40	445.50	0.89	1.52
FE 4	0.40	454.50	0.91	1.44
Target	0.40	450.00		0.05

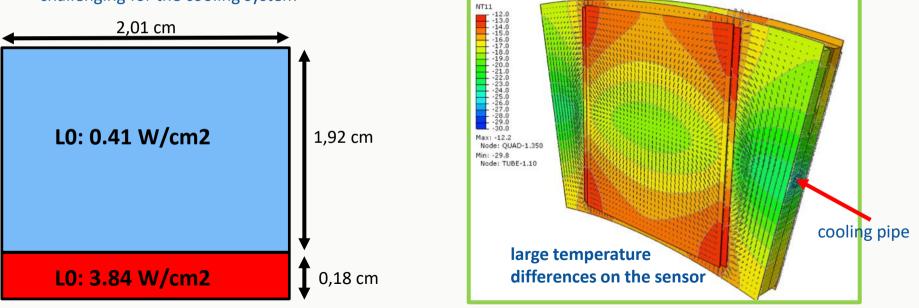
required current depends on hit-rate
hit-rate can only be roughly estimated from sim
variations of up to 10% seen between simulatic
1% variation in offset and slope in combination



VIN [V]



- significant fraction of total module power is dissipated on the chip periphery
  - almost 40% of the total power dissipated in less than 10% of the chip area
  - challenging for the cooling system

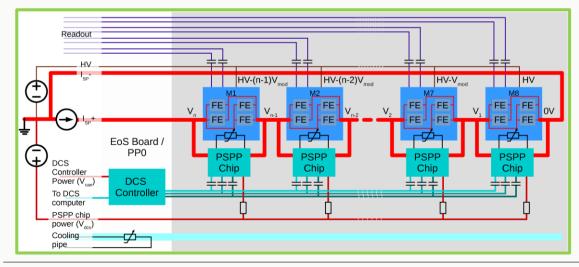


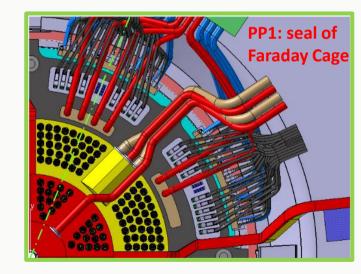


# HIGH VOLTAGE DISTRIBUTION ISSUES

- we can not put enough cables into the detector to provide an individual HV line for each sensor
  - parallel distribution of sensor bias voltage to a subset or all modules in a serial powering chain
  - HV referenced to local module ground different effective bias voltage on every single sensor
  - long chains with 3D sensors not desirable

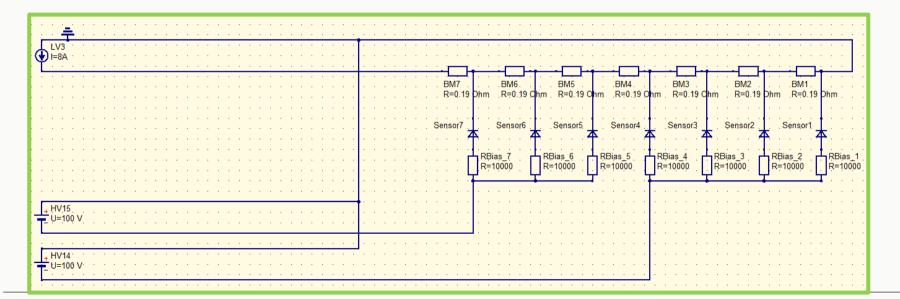
 $\rightarrow$  depletion voltage as high as 10 V, breakdown voltage as low as 20V





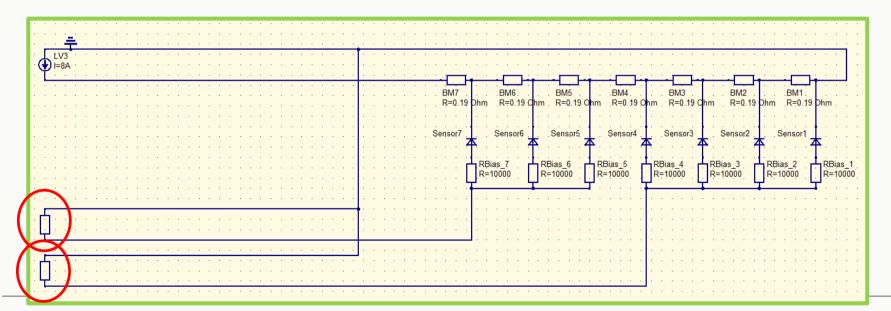


- our grounding and shielding rules require us to tie the return lines of all power supplies to each other in the detector
  - in combination with our current power supplies, this generates a potential problem
    - HV power supplies act as high-ohmic resistors when switched off



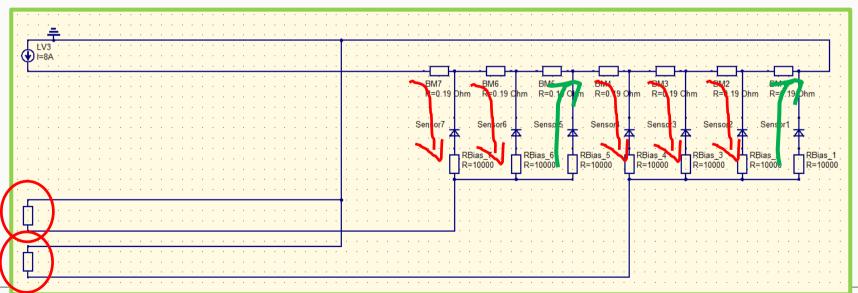


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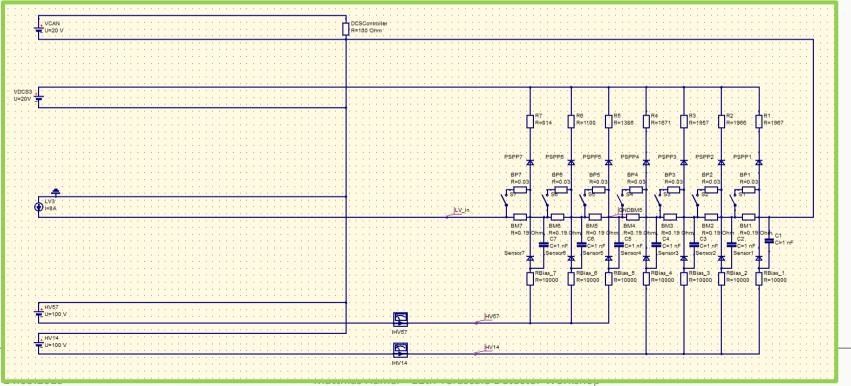
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  - in combination with our current power supplies, this generates a potential problem
    - HV power supplies act as high-ohmic resistors when switched off
    - LV on  $\rightarrow$  small effective bias on each sensor  $\rightarrow$  return path through modules has lower resistance than HV PSU





# **OTHER SYSTEM ASPECTS**

- a similar effect with the PSPP chips
  - our current LV power supplies are shorted when switched off; VDCS generates a negative voltage drop on FE chips

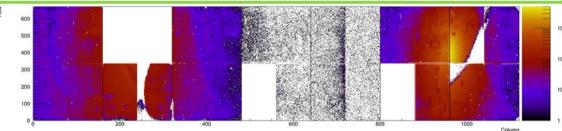


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## SERIAL POWERING IN ACTION

- several prototypes have been built by now
  - proof of principle at Bonn some time ago
  - prototype with realistic services, power supplies, local supports at CERN
  - long serial powering chain (13 modules) in Liverpool

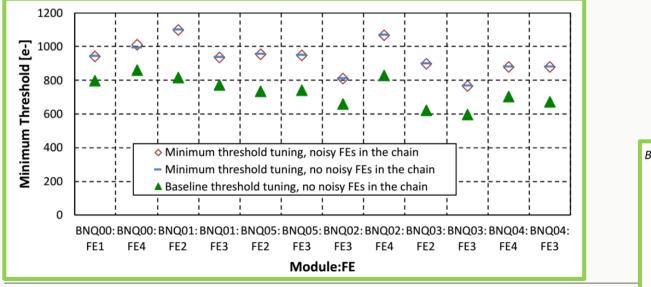


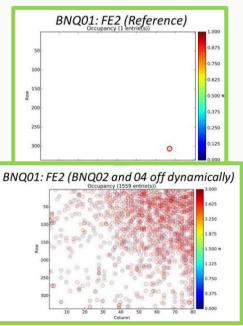
simultaneous source scan with full prototype





- effects of transients in the LV line
  - noise pickup
  - with FE-I4 modules, oscillations can be triggered by overloading the SLDO regulator (noisy module)
  - effect on remaining modules was tested: low to no effect



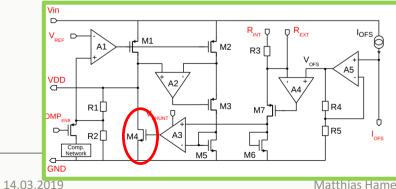


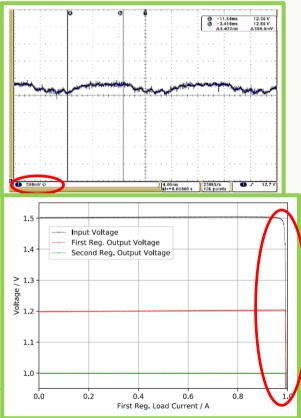
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## UPGRADES FOR SERIAL POWERING

- protection mechanisms for front-ends required:
  - large transients can be dangerous for modules
- FE chips for ATLAS and CMS upgrades will have two protection mechanisms:
  - overvoltage protection
    - $\rightarrow$  simply voltage clamp (2V) in parallel to regulator
  - under-shunt-current protection
    - → shunt current is sensed and output voltage of regulator is lowered if this shunt current is too small







- Serial Powering is Standard Solution for the ATLAS and CMS Pixel Detector Upgrades
  - lower losses on powering cables
  - less material in the detector
  - not DC-DC converters in the detector
- Serial Powering comes with several challenges:
  - parallel powering of front-end chips on modules
  - distribution of high voltage to sensors
  - safe operation of chain in case of noisy front-ends
  - thermal management of the modules
  - right choice of power supplies